

Notice of References Cited	Application/Control No. 10/715,376	Applicant(s)/Patent Under Reexamination SUN ET AL.	
	Examiner Thinh T. Nguyen	Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,744,086	06-2004	Daughton et al.	257/295
*	B	US-5,917,749	06-1999	Chen et al.	365/173
*	C	US-6,341,053	01-2002	Nakada et al.	360/324.2
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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	P					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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